#### features

- Dual-Channel High-Side MOSFET Drivers
- IN1: 3 V to 13 V; IN2: 3 V to 5.5 V
- Inrush Current Limiting With dv/dt Control
- Independent Circuit-Breaker Control With Programmable Current Limit and Transient Timer
- CMOS- and TTL-Compatible Enable Input
- Low, 5-μA Standby Supply Current . . . Max
- Available in 16-Pin SOIC and TSSOP Package
- –40°C to 85°C Ambient Temperature Range
- Electrostatic Discharge Protection

#### applications

- Hot-Swap/Plug/Dock Power Management
- Hot-Plug PCI, Device Bay
- Electronic Circuit Breaker

#### description

The TPS2320 and TPS2321 are dual-channel hot-swap controllers that use external N-channel MOSFETs as high-side switches in power applications. Features of these devices, such as overcurrent protection (OCP), inrush-current control, and separation of load transients from actual load increases, are critical requirements for hot-swap applications.

The TPS2320/21 devices incorporate undervoltage lockout (UVLO) to ensure the device is off at startup. Each internal charge pump, capable of driving multiple MOSFETs, provides enough gate-drive voltage to fully enhance the N-channel MOSFETs. The charge pumps control both the rise times and fall times (dv/dt) of the MOSFETs, reducing power transients during power up/down. The circuit-breaker functionality combines the ability to sense overcurrent conditions with a timer function; this allows designs such as DSPs, that may have high peak currents during power-state transitions, to disregard transients for a programmable period.

ТА	HOT-SWAP CONTROLLER DESCRIPTION	PIN	PACKAGES			
	HOT-SWAP CONTROLLER DESCRIPTION	COUNT	ENABLE	ENABLE		
	Dual-channel with independent OCP and adjustable PG	20	TPS2300IPW	TPS2301IPW		
	Dual-channel with interdependent OCP and adjustable PG	20	TPS2310IPW	TPS2311IPW		
-40°C to 85°C	Dual-channel with independent OCP	16	TPS2320ID TPS2320IPW	TPS2321ID TPS2321IPW		
	Single-channel with OCP and adjustable PG	14	TPS2330ID TPS2330IPW	TPS2331ID TPS2331IPW		

**AVAILABLE OPTIONS** 

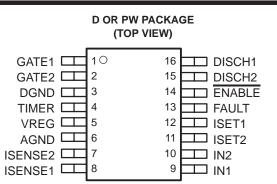
<sup>†</sup> The packages are available left-end taped and reeled (indicated by the R suffix on the device type; e.g., TPS2321IPWR).



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

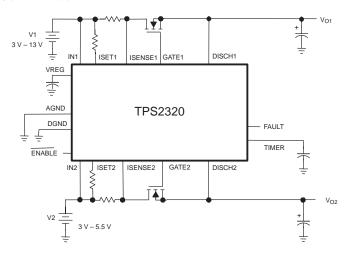
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



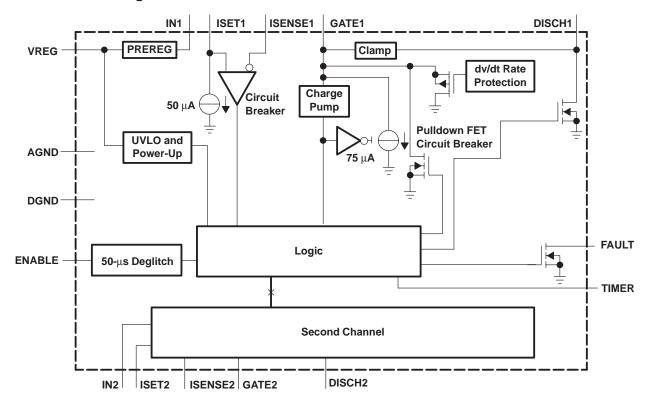


NOTE: Terminal 14 is active high on TPS2321.

#### typical application



# functional block diagram



## **Terminal Functions**

TERMINAL NAME	NO.	I/O	DESCRIPTION
AGND	6	1	Analog ground, connects to DGND as close as possible
DGND	3	1	Digital ground
DISCH1	16	0	Discharge transistor 1
DISCH2	15	0	Discharge transistor 2
ENABLE/ ENABLE	14	I	Active low (TPS2320) or active high enable (TPS2321)
FAULT	13	0	Overcurrent fault, open-drain output
GATE1	1	0	Connects to gate of channel 1 high-side MOSFET
GATE2	2	0	Connects to gate of channel 2 high-side MOSFET
IN1	9	I	Input voltage for channel 1
IN2	10	Т	Input voltage for channel 2
ISENSE1	8	I	Current-sense input channel 1
ISENSE2	7	I	Current-sense input channel 2
ISET1	12	I	Adjusts circuit-breaker threshold with resistor connected to IN1
ISET2	11	Ι	Adjusts circuit-breaker threshold with resistor connected to IN2
TIMER	4	0	Adjusts circuit-breaker deglitch time
VREG	5	0	Connects to bypass capacitor, for stable operation



#### detailed description

**DISCH1, DISCH2** – DISCH1 and DISCH2 should be connected to the sources of the external N-channel MOSFET transistors connected to GATE1 and GATE2, respectively. These pins discharge the loads when the MOSFET transistors are disabled. They also serve as reference-voltage connections for internal gate voltage-clamp circuitry.

**ENABLE** or ENABLE – ENABLE for TPS2320 is active low. ENABLE for TPS2321 is active high. When the controller is enabled, both GATE1 and GATE2 voltages will power up to turn on the external MOSFETs. When the ENABLE pin is pulled high for TPS2320 or the ENABLE pin is pulled low for TPS2321 for more than 50  $\mu$ s, the gate of the MOSFET is discharged at a controlled rate by a current source, and a transistor is enabled to discharge the output bulk capacitance. In addition, the device turns on the internal regulator PREREG (see VREG) when enabled and shuts down PREREG when disabled so that total supply current is much less than 5  $\mu$ A.

**FAULT** – FAULT is an open-drain overcurrent flag output. When an overcurrent condition in either channel is sustained long enough to charge TIMER to 0.5 V, the overcurrent channel latches off and pulls FAULT low. The other channel will run normally if not in overcurrent.

**GATE1, GATE2** – GATE1 and GATE2 connect to the gates of external N-channel MOSFET transistors. When the device is enabled, internal charge-pump circuitry pulls these pins up by sourcing approximately 15  $\mu$ A to each. The turnon slew rates depend upon the capacitance present at the GATE1 and GATE2 terminals. If desired, the turnon slew rates can be further reduced by connecting capacitors between these pins and ground. These capacitors also reduce inrush current and protect the device from false overcurrent triggering during powerup. The charge-pump circuitry will generate gate-to-source voltages of 9 V–12 V across the external MOSFET transistors.

**IN1, IN2** – IN1 and IN2 should be connected to the power sources driving the external N-channel MOSFET transistors connected to GATE1 and GATE2, respectively. The TPS2320/TPS2321 draws its operating current from IN1, and both channels will remain disabled until the IN1 power supply has been established. The IN1 channel has been constructed to support 3-V, 5-V, or 12-V operation, while the IN2 channel has been constructed to support 3-V operation

**ISENSE1, ISENSE2, ISET1, ISET2** – ISENSE1 and ISENSE2, in combination with ISET1 and ISET2, implement overcurrent sensing for GATE1 and GATE2. ISET1 and ISET2 set the magnitude of the current that generates an overcurrent fault, through external resistors connected to ISET1 and ISET2. An internal current source draws  $50 \,\mu$ A from ISET1 and ISET2. With a sense resistor from IN1 to ISENSE1 or from IN2 to ISENSE2, which is also connected to the drains of external MOSFETs, the voltage on the sense resistor reflects the load current. An overcurrent condition is assumed to exist if ISENSE1 is pulled below ISET1 or if ISENSE2 is pulled below ISET2.

**TIMER** – A capacitor on TIMER sets the time during which the power switch can be in overcurrent before turning off. When the overcurrent protection circuits sense an excessive current, a current source is enabled which charges the capacitor on TIMER. Once the voltage on TIMER reaches approximately 0.5 V, the circuit-breaker latch is set and the power switch is latched off. Power must be recycled or the ENABLE pin must be toggled to restart the controller. In high-power or high-temperature applications, a minimum 50-pF capacitor is strongly recommended from TIMER to ground, to prevent any false triggering.

**VREG** – The VREG pin is the output of an internal low-dropout voltage regulator. This regulator draws current from IN1. A 0.1- $\mu$ F ceramic capacitor should be connected between VREG and ground. VREG can be connected to IN1, IN2, or to a separated power supply through a low-resistance resistor. However, the voltage on VREG must be less than 5.5 V.



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### absolute maximum ratings over operating free-air temperature (unless otherwise noted)<sup>†</sup>

Input voltage range: V <sub>I(IN1)</sub> , V <sub>I(ISENSE1)</sub> , V <sub>I(ISET1)</sub> , V <sub>I(ENABLE)</sub>
V <sub>I(IN2)</sub> , V <sub>I(ISENSE2)</sub> , V <sub>I(ISET2)</sub>
Output voltage range: V <sub>O(GATE1)</sub>
V <sub>O(GATE2)</sub>
V <sub>O</sub> (DISCH1), V <sub>O</sub> (FAULT), V <sub>O</sub> (VREG), V <sub>O</sub> (DISCH2), V <sub>O</sub> (TIMER), –0.3 V to 15V
Sink current range: I <sub>GATE1</sub> , I <sub>GATE2</sub> , I <sub>DISCH1</sub> , I <sub>DISCH2</sub> ,
ITIMER, IFAULT
Operating virtual junction temperature range, T <sub>J</sub>
Storage temperature range, T <sub>stg</sub>
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltages are respect to DGND.

#### DISSIPATION RATING TABLE

PACKAGE	T <sub>A</sub> ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING	T <sub>A</sub> = 85°C POWER RATING
PW-16	823 mW	10.98 mW/°C	329 mW	165 mW
D-16	674 mW	8.98 mW/°C	270 mW	135 mW

#### recommended operating conditions

		MIN	NOM MAX	UNIT
Input voltage, V <sub>I</sub>	VI(IN1), VI(ISENSE1), VI(ISET1)	3	13	V
	VI(IN2), VI(ISENSE2), VI(ISET2)	3	5.5	v
VREG voltage, VO(VREG), wh	en VREG is directly connected to IN1			V
Operating virtual junction temp	erature, TJ	-40	100	°C



# electrical characteristics over recommended operating temperature range (–40°C < $T_A$ < 85°C), 3 V $\leq$ V<sub>I(IN1)</sub> $\leq$ 13 V, 3 V $\leq$ V<sub>I(IN2)</sub> $\leq$ 5.5 V (unless otherwise noted)

#### general

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
II(IN1)	Input current, IN1	$V_{I(ENABLE)} = 5 V (TPS2321),$		0.5	1	mA
II(IN2)	Input current, IN2	$VI(\overline{ENABLE}) = 0 V (TPS2320)$		75	200	μA
II(stby)		VI(ENABLE) = 0 V (TPS2321),			5	μA
(SDy)	ISENSE1, ISENSE2, ISET1, and ISET2)	VI(ENABLE) = 5 V (TPS2320)			Ũ	port

#### GATE1

PA	ARAMETER	TEST CONDITION	ONS	MIN	TYP	MAX	UNIT
VG(GATE1_3V)		500 4	V <sub>I(IN1)</sub> = 3 V	9	11.5		
VG(GATE1_4.5V)	Gate voltage	I <sub>I(GATE1)</sub> = 500 nA, DISCH1 open	V <sub>I(IN1)</sub> = 4.5 V	10.5	14.5		V
VG(GATE1_10.8V)			V <sub>I(IN1)</sub> = 10.8 V	16.8	21		
VC(GATE1)	Clamping voltage, GATE1 to DISCH1			9	10	12	V
IS(GATE1)	Source current, GATE1	$\begin{array}{l} 3 \ V \leq V_{I(IN1)} \leq 13.2 \ V, \ 3 \ V \leq V_{O}(VREG) \leq 5.5 \ V, \\ V_{I}(GATE1) = V_{I}(IN1) + 6 \ V \\ 3 \ V \leq V_{I}(IN1) \leq 13.2 \ V, \ 3 \ V \leq V_{O}(VREG) \leq 5.5 \ V, \\ V_{I}(GATE1) = V_{I}(IN1) \end{array}$		10	14	20	μΑ
	Sink current, GATE1			50	75	100	μΑ
			V <sub>I(IN1)</sub> = 3 V		0.5		
<sup>t</sup> r(GATE1)	Rise time, GATE1	$C_g$ to GND = 1 nF (see Note 2)	V <sub>I(IN1)</sub> = 4.5 V		0.6		ms
			V <sub>I(IN1)</sub> = 10.8 V		1		
			V <sub>I(IN1)</sub> = 3 V		0.1		
<sup>t</sup> f(GATE1)	Fall time, GATE1	$C_g$ to GND = 1 nF (see Note 2)	V <sub>I(IN1)</sub> = 4.5 V		0.12		ms
			V <sub>I(IN1)</sub> = 10.8 V		0.2		

#### GATE2

PAR	AMETER	TEST CONDITIONS			MIN	TYP	MAX	UNIT	
VG(GATE2_3V)	Gate voltage	140 ATEN = 500 pA		V <sub>I(IN2)</sub> = 3 V	9	11.7		V	
VG(GATE2_4.5V)	Gale voltage	I <sub>I(GATE2)</sub> = 500 nA,	DISCI IZ OPEN	V <sub>I(IN2)</sub> = 4.5 V	10.5	14.7		v	
VC(GATE2)	Clamping voltage, GATE2 to DISCH2				9	10	12	V	
IS(GATE2)	Source current, GATE2	$3 V \le V_{I(IN2)} \le 5.5 V$ VI(GATE2) = VI(IN2)	$3 V \le V_{I(IN2)} \le 5.5 V$ , $3 V \le V_{O(VREG)} \le 5.5 V$ , $V_{I(GATE2)} = V_{I(IN2)} + 6 V$			14	20	μΑ	
	Sink current, GATE2	$3 V \le V_{I(IN2)} \le 5.5 V$ , $3 V \le V_{O(VREG)} \le 5.5 V$ , $V_{I(GATE2)} = V_{I(IN2)}$			50	75	100	μA	
+ (0.1770)	Rise time, GATE2	C <sub>g</sub> to GND = 1 nF	V <sub>I(IN2)</sub> = 3 V			0.5			
<sup>t</sup> r(GATE2)	Rise time, GATE2	(see Note 2)	V <sub>I(IN2)</sub> = 4.5 V			0.6		ms	
+	Fall time, GATE2	C <sub>g</sub> to GND = 1 nF	V <sub>I(IN2)</sub> = 3 V	V <sub>O(VREG)</sub> = 3 V		0.1			
<sup>t</sup> f(GATE2)	Fair unie, GATEZ	(see Note 2)	V <sub>I(IN2)</sub> = 4.5 V			0.12		ms	

NOTE 2: Specified, but not production tested.



# electrical characteristics over recommended operating temperature range (–40°C < T<sub>A</sub> < 85°C), 3 V $\leq$ V<sub>I(IN1)</sub> $\leq$ 13 V, 3 V $\leq$ V<sub>I(IN2)</sub> $\leq$ 5.5 V ( unless otherwise noted) (continued)

#### TIMER

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VOT(TIMER)	Threshold voltage, TIMER		0.4	0.5	0.6	V
	Charge current, TIMER	$V_{I}(TIMER) = 0 V$	35	50	65	μA
	Discharge current, TIMER	VI(TIMER) = 1 V	1	2.5		mA

#### circuit breaker

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VIT(CB)	Undervoltage voltage, circuit breaker	$R_{ISET_X} = 1 \ k\Omega$	40	50	60	mV
IB(ISENSEx)	Input bias current, ISENSEx			0.1	5	μA
	Discharge ourrest CATEY	$V_{O(GATEx)} = 4 V$	400	800		mA
	Discharge current, GATEx	V <sub>O(GATEx)</sub> = 1 V	25	150		mA
<sup>t</sup> pd(CB)	Propagation (delay) time, comparator inputs to gate output	$C_g = 50 \text{ pF},$ 10 mV overdrive, (50% to 10%) $C_O(\text{timer}) = 50 \text{ pF}$		1.3		μs

#### ENABLE, active low (TPS2320)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VIH(ENABLE)	High-level input voltage, ENABLE		2			V
VIL(ENABLE)	Low-level input voltage, ENABLE				0.8	V
RI(ENABLE)	<u>Input pull</u> up resistance, ENABLE	See Note 3	100	200	300	kΩ
<sup>t</sup> d_off(ENABLE)	Turnoff delay time, ENABLE	VI(ENABLE) increasing above stop threshold; 100 ns rise time, 20 mV overdrive (see Note 2)		60		μs
<sup>t</sup> d_on(ENABLE)	Turnon delay time, ENABLE	VI(ENABLE) decreasing below start threshold; 100 ns fall time, 20 mV overdrive (see Note 2)		125		μs

NOTES: 2. Specified, but not production tested.

3. Test I<sub>O</sub> of ENABLE at V<sub>I</sub>(ENABLE) = 1 V and 0 V, then R<sub>I</sub>(ENABLE) = 
$$\frac{1 \text{ V}}{I_O_0 \text{ V} - I_O_1 \text{ V}}$$

# ENABLE, active high (TPS2321)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VIH(ENABLE)	High-level input voltage, ENABLE		2			V
VIL(ENABLE)	Low-level input voltage, ENABLE				0.7	V
RI(ENABLE)	Input pulldown resistance, ENABLE		100	150	300	kΩ
<sup>t</sup> d_on(ENABLE)	Turnon delay time, ENABLE	V <sub>I(ENABLE)</sub> increasing above start threshold; 100 ns rise time, 20 mV overdrive (see Note 2)		85		μs
<sup>t</sup> d_off(ENABLE)	Turnoff delay time, ENABLE	VI(ENABLE) decreasing below stop threshold; 100 ns fall time, 20 mV overdrive (see Note 2)		100		μs

NOTE 2: Specified, but not production tested.

#### PREREG

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
VREG	PREREG output voltage	$4.5 \le V_{I(IN1)} \le 13 V$	3.5	4.1	5.5	V
Vdrop_PREREG	PREREG dropout voltage	$V_{I(IN1)} = 3 V$			0.1	V



# electrical characteristics over recommended operating temperature range (–40°C < $T_A$ < 85°C), 3 V $\leq$ V<sub>I(IN1)</sub> $\leq$ 13 V, 3 V $\leq$ V<sub>I(IN2)</sub> $\leq$ 5.5 V (unless otherwise noted) (continued)

#### **VREG UVLO**

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
VOT(UVLOstart)	Output threshold voltage, start		2.75	2.85	2.95	V
VOT(UVLOstop)	Output threshold voltage, stop		2.65	2.78		V
V <sub>hys</sub> (UVLO)	Hysteresis		50	75		mV
	UVLO sink current, GATEx	$V_{I(GATEx)} = 2 V$	10			mA

#### **FAULT** output

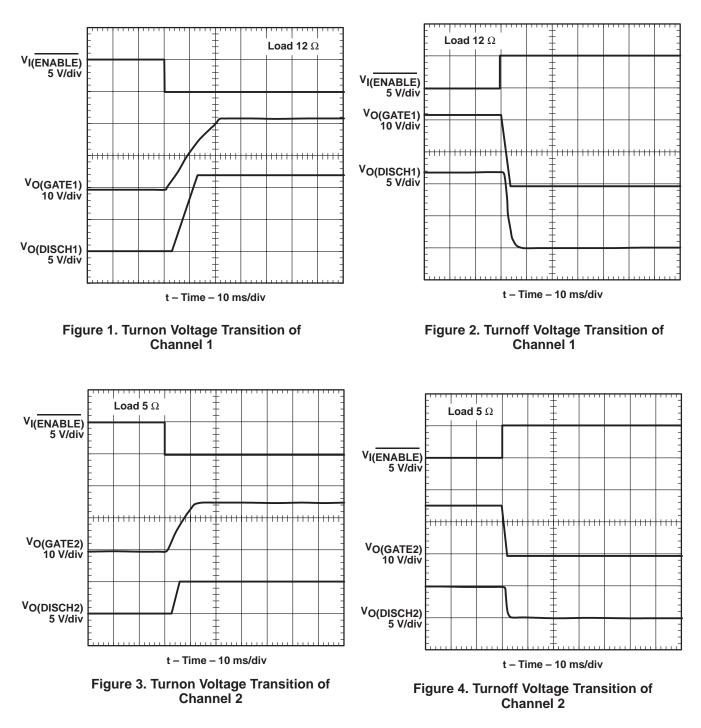
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
VO(sat)(FAULT)	Output saturation voltage, FAULT	I <sub>O</sub> = 2 mA			0.4	V
Ilkg(FAULT)	Leakage current, FAULT	V <sub>O(FAULT)</sub> = 13 V			1	μΑ

#### **DISCH1 and DISCH2**

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
IDISCH	Discharge current, DISCHx	$V_{I(DISCHx)} = 1.5 V, V_{I(VIN1)} = 5 V$	5	10		mA
VIH(DISCH)	Discharge on high-level input voltage		2			V
VIL(DISCH)	Discharge on low-level input voltage				1	V



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# PARAMETER MEASUREMENT INFORMATION

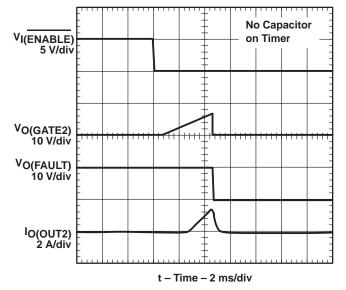
**No Capacitor** 

on Timer

No Capacitor ł VI(ENABLE) VI(ENABLE) on Timer 5 V/div + 5 V/div V<sub>O(GATE1)</sub> 10 V/div Ŧ + VO(GATE1) 10 V/div VO(FAULT) 10 V/div VO(FAULT) + 10 V/div + lO(OUT1) 2 A/div IO(OUT1) 2 A/div t – Time – 5 ms/div t - Time - 1 ms/div

# PARAMETER MEASUREMENT INFORMATION





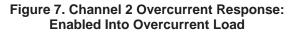


Figure 6. Channel 1 Overcurrent Response: an Overcurrent Load Plugged Into the Enabled Board

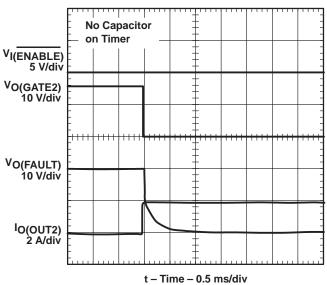
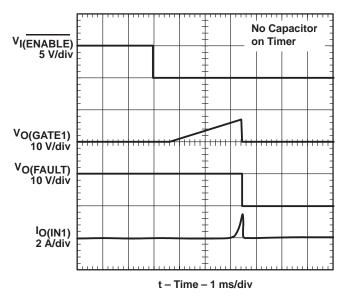


Figure 8. Channel 2 Overcurrent Response: an Overcurrent Load Plugged Into the Enabled Board



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# PARAMETER MEASUREMENT INFORMATION



\*\*\*\*\*

t – Time – 5 ms/div

Figure 11. Channel 1 – Hot Plug

**No Capacitor** 

on Timer

V<sub>I(IN1)</sub> 10 V/div

VO(GATE1)

10 V/div

VO(OUT1) 10 V/div

IO(OUT1) Ì A/div

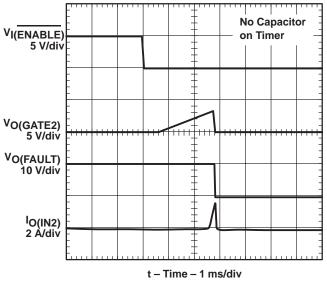


Figure 10. Channel 2 – Enabled Into Short Circuit

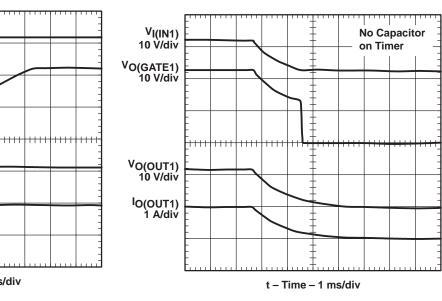
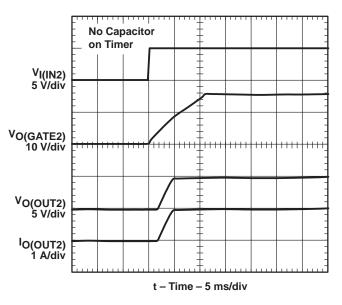


Figure 12. Channel 1 – Hot Removal



# PARAMETER MEASUREMENT INFORMATION





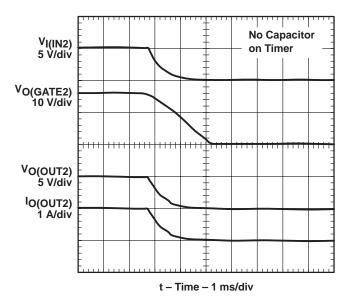
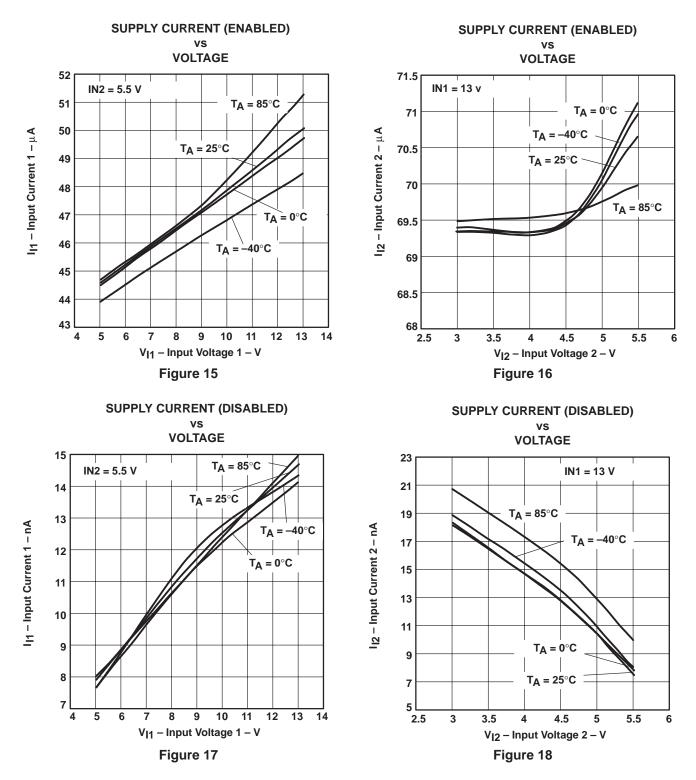


Figure 14. Channel 2 – Hot Removal

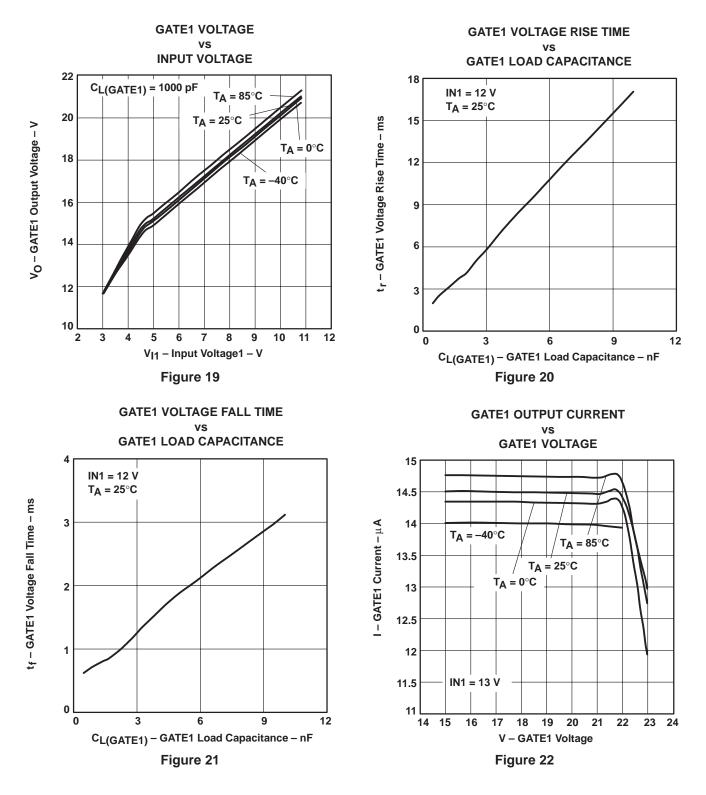


# **TYPICAL CHARACTERISTICS**



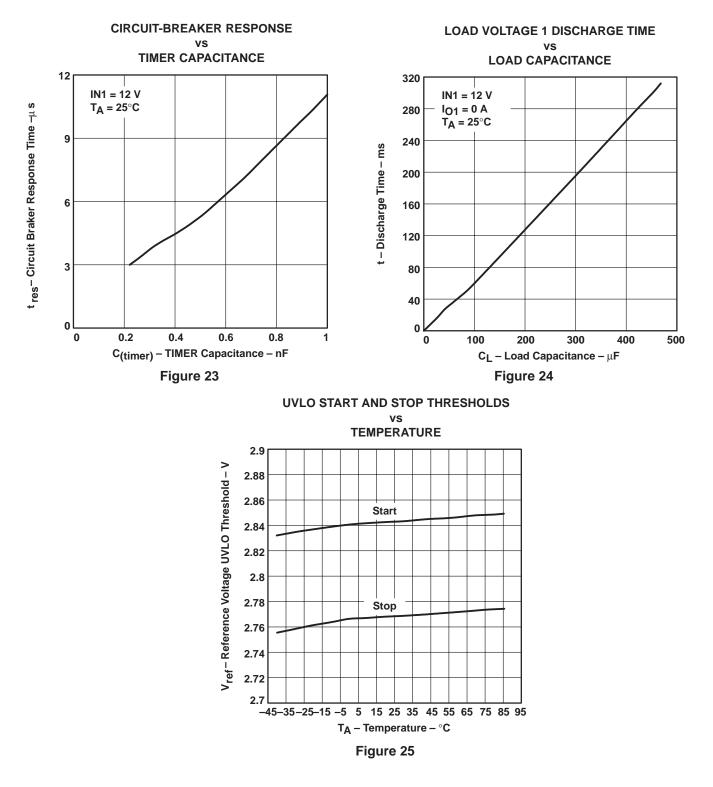


#### **TYPICAL CHARACTERISTICS**





## **TYPICAL CHARACTERISTICS**





# APPLICATION INFORMATION

# typical application diagram

Figure 26 shows a typical dual hot-swap application. The pullup resistor at FAULT should be relatively large (e.g., 100 k $\Omega$ ) to reduce power loss, unless it is required to drive a large load.

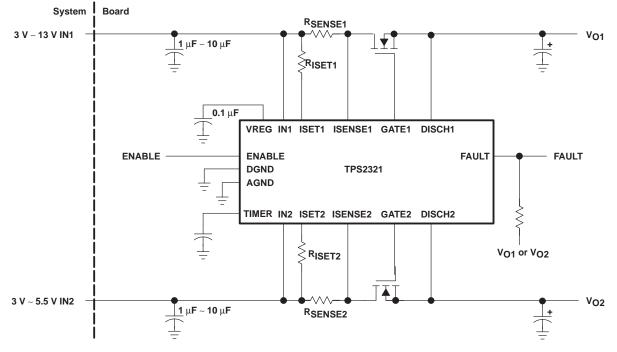


Figure 26. Typical Dual Hot-Swap Application

#### input capacitor

A 0.1- $\mu$ F ceramic capacitor in parallel with a 1- $\mu$ F ceramic capacitor should be placed on the input power terminals near the connector on the hot-plug board to help stabilize the voltage rails on the cards. The TPS2320/01 does not need to be mounted near the connector or to these input capacitors. For applications with more severe power environments, a 2.2- $\mu$ F, or higher, ceramic capacitor is recommended near the input terminals of the hot-plug board. A bypass capacitor for IN1 and for IN2 should be placed close to the device.

#### output capacitor

A 0.1-µF ceramic capacitor is recommended per load on the TPS2320/21; these capacitors should be placed close to the external FETs and to TPS2320/21. A larger bulk capacitor is also recommended on the load. The value of the bulk capacitor should be selected based on the power requirements and the transients generated by the application.

#### external FET

To deliver power from the input sources to the loads, each channel needs an external N-channel MOSFET. A few widely used MOSFETs are shown in Table 1. But many other MOSFETs on the market can also be used with TPS23xx in hot-swap systems.



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# **APPLICATION INFORMATION**

CURRENT RANGE (A)	PART NUMBER	DESCRIPTION	MANUFACTURER
	IRF7601	N-channel, $r_{DS(on)} = 0.035 \Omega$ , 4.6 A, Micro-8	International Rectifier
0 to 2	MTSF3N03HDR2	N-channel, $r_{DS(on)}$ = 0.040 $\Omega$ , 4.6 A, Micro-8	ON Semiconductor
	MMSF5N02HDR2	Dual N-channel, $r_{DS(on)} = 0.04 \Omega$ , 5 A, SO-8	ON Semiconductor
	IRF7401	N-channel, r <sub>DS(on)</sub> = 0.022 Ω, 7 A, SO-8	International Rectifier
2 to 5	MMSF5N02HDR2	N-channel, $r_{DS(on)} = 0.025 \Omega$ , 5 A, SO-8	ON Semiconductor
2 10 5	IRF7313	Dual N-channel, $r_{DS(on)} = 0.029 \Omega$ , 5.2 A, SO-8	International Rectifier
	SI4410	N-channel, r <sub>DS(on)</sub> = 0.020 Ω, 8 A, SO-8	Vishay Dale
5 to 10	IRLR3103	N-channel, $r_{DS(on)}$ = 0.019 $\Omega$ , 29 A, d-Pak	International Rectifier
5.010	IRLR2703	N-channel, $r_{DS(on)}$ = 0.045 $\Omega$ , 14 A, d-Pak	International Rectifier

#### Table 1. Some Available N-Channel MOSFETs

#### timer

For most applications, a minimum capacitance of 50 pF is recommended to prevent false triggering. A capacitor should be connected between TIMER and ground. The presence of an overcurrent condition on either channel of the TPS2320/TPS2321 causes a 50- $\mu$ A current source to begin charging this capacitor. If the overcurrent condition persists until the capacitor has been charged to approximately 0.5 V, the TPS2320/TPS2321 will latch off the offending channels and will pull the FAULT pin low. The timer capacitor can be made as large as desired to provide additional time delay before registering a fault condition.

#### output-voltage slew-rate control

When enabled, the TPS2320/TPS2321 controllers supply the gates of each external MOSFET transistor with a current of approximately 15  $\mu$ A. The slew rate of the MOSFET source voltage is thus limited by the gate-to-drain capacitance C<sub>qd</sub> of the external MOSFET capacitor to a value approximating:

$$\frac{dvs}{dt} = \frac{15 \ \mu A}{C_{gd}}$$

If a slower slew rate is desired, an additional capacitance can be connected between the gate of the external MOSFET and ground.

#### **VREG** capacitor

The internal voltage regulator connected to VREG requires an external capacitor to ensure stability. A  $0.1-\mu F$  or  $0.22-\mu F$  ceramic capacitor is recommended.



# APPLICATION INFORMATION

# gate-drive circuitry

The TPS2320/TPS2321 includes four separate features associated with each gate-drive terminal:

- A charging current of approximately 15 μA is applied to enable the external MOSFET transistor. This current is generated by an internal charge pump that can develop a gate-to-source potential (referenced to DISCH1 or DISCH2) of 9 V–12 V. DISCH1 and DISCH2 must be connected to the respective external MOSFET source terminals to ensure proper operation of this circuitry.
- A discharge current of approximately 75 µA is applied to disable the external MOSFET transistor. Once the transistor gate voltage has dropped below approximately 1.5 V, this current is disabled and the UVLO discharge driver is enabled instead. This feature allows the part to enter a low-current shutdown mode while ensuring that the gates of the external MOSFET transistors remain at a low voltage.
- During a UVLO condition, the gates of both MOSFET transistors are pulled down by internal PMOS transistors. These transistors continue to operate even if IN1 and IN2 are both at 0 V. This circuitry also helps hold the external MOSFET transistors off when power is suddenly applied to the system.
- During an overcurrent fault condition, the external MOSFET transistor that exhibited an overcurrent condition will be rapidly turned off by an internal pulldown circuit capable of pulling in excess of 400 mA (at 4 V) from the pin. Once the gate has been pulled below approximately 1.5 V, this driver is disengaged and the UVLO driver is enabled instead. If one channel experiences an overcurrent condition and the other does not, then only the channel that is conducting excessive current will be turned off rapidly. The other channel will continue to operate normally.

## setting the current-limit circuit-breaker threshold

Using Channel 1 as an example, the current sensing resistor  $R_{ISENSE1}$  and the current-limit-setting resistor  $R_{ISET1}$  determine the current limit of the channel, and can be calculated by the following equation:

$$I_{LMT1} = \frac{R_{ISET1} \times 50 \times 10^{-6}}{R_{ISENSE1}}$$

Typically  $R_{ISENSE1}$  is very small (0.001  $\Omega$  to 0.1  $\Omega$ ). If the trace and solder-junction resistances between the junction of  $R_{ISENSE1}$  and ISENSE1 and the junction of  $R_{ISENSE1}$  and  $R_{ISET1}$  are greater than 10% of the  $R_{ISENSE1}$  value, then these resistance values should be added to the  $R_{ISENSE1}$  value used in the calculation above.

The above information and calculation also apply to Channel 2. Table 2 shows some of the current sense resistors available in the market.

CURRENT RANGE (A)	PART NUMBER	DESCRIPTION	MANUFACTURER	
0 to 1	WSL-1206, 0.05 1%	0.05 Ω, 0.25 W, 1% resistor		
1 to 2	WSL-1206, 0.025 1%	0.025 Ω, 0.25 W, 1% resistor		
2 to 4	WSL-1206, 0.015 1%	0.015 Ω, 0.25 W, 1% resistor	Vishay Dale	
4 to 6	WSL-2010, 0.010 1%	0.010 Ω, 0.5 W, 1% resistor	VISITAY Date	
6 to 8	WSL-2010, 0.007 1%	0.007 Ω, 0.5 W, 1% resistor		
8 to 10	WSR-2, 0.005 1%	0.005 Ω, 0.5 W, 1% resistor		

Table 2. Some Current Sense Resistors



**APPLICATION INFORMATION** 

### undervoltage lockout (UVLO)

The TPS2320/TPS2321 includes an undervoltage lockout (UVLO) feature that monitors the voltage present on the VREG pin. This feature will disable both external MOSFETs if the voltage on VREG drops below 2.78 V (nominal) and will re-enable normal operation when it rises above 2.85 V (nominal). Since VREG is fed from IN1 through a low-dropout voltage regulator, the voltage on VREG will track the voltage on IN1 within 50 mV. While the undervoltage lockout is engaged, both GATE1 and GATE2 are held low by internal PMOS pulldown transistors, ensuring that the external MOSFET transistors remain off at all times, even if all power supplies have fallen to 0 V.

#### single-channel operation

Some applications may require only a single external MOS transistor. Such applications should use GATE1 and the associated circuitry (IN1, ISENSE1, ISET1, DISCH1). The IN2 pin should be grounded to disable the circuitry associated with the GATE2 pin.

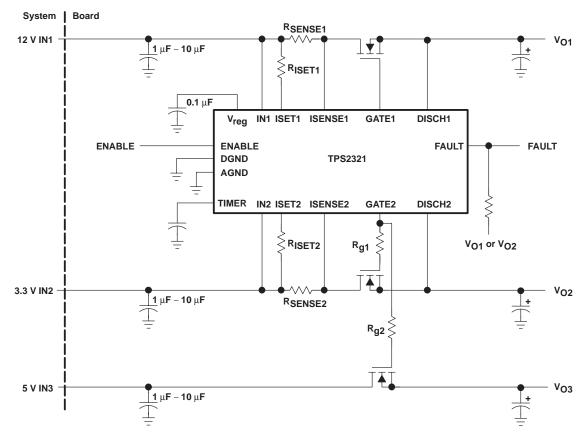
#### power-up control

The TPS2320/TPS2321 includes a 500  $\mu$ s (nominal) startup delay that ensures that internal circuitry has sufficient time to start before the device begins turning on the external MOSFETs. This delay is triggered only upon the rapid application of power to the circuit. If the power supply ramps up slowly, the undervoltage lockout circuitry will provide adequate protection against undervoltage operation.

#### 3-channel hot-swap application

Some applications require hot-swap control of up to three voltage rails, but may not explicitly require the sensing of the status of the output power on all three of the voltage rails. One such application is device bay, where dv/dt control of 3.3 V, 5 V, and 12 V is required. By using Channel 2 to drive both the 3.3-V and 5-V power rails and Channel 1 to drive the 12-V power rail, as is shown below, TPS2320/01 can deliver three different voltages to three loads while monitoring the status of two of the loads.

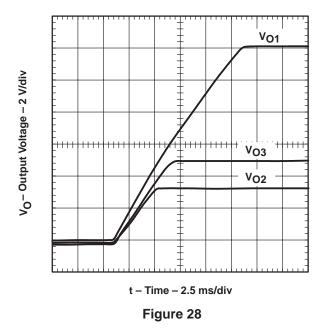




#### **APPLICATION INFORMATION**



Figure 28 shows ramp-up waveforms of the three output voltages.



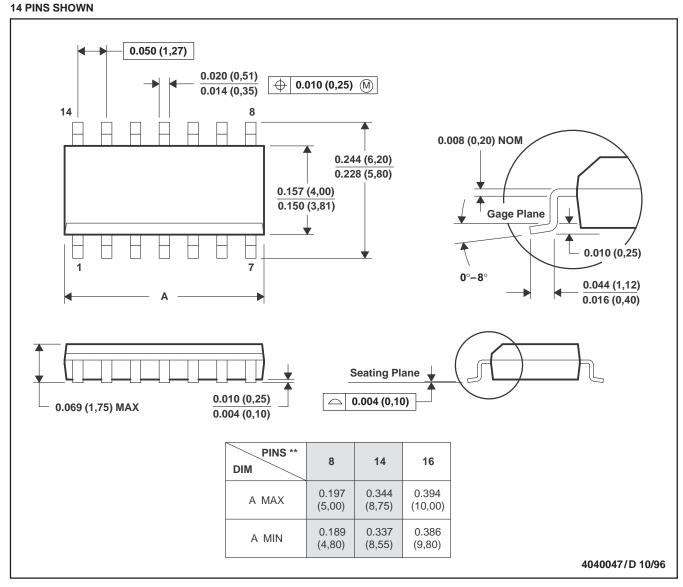


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**MECHANICAL DATA** 

#### D (R-PDSO-G\*\*)

#### PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-012

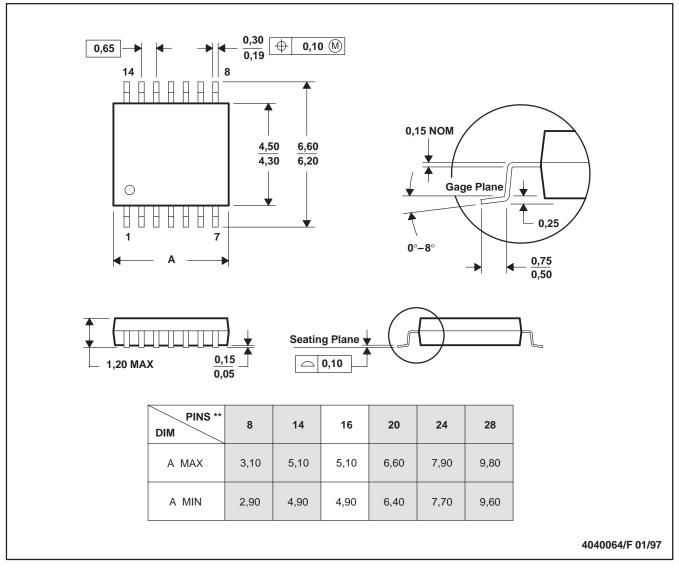


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#### **MECHANICAL DATA**

#### PLASTIC SMALL-OUTLINE PACKAGE

PW (R-PDSO-G\*\*) **14 PINS SHOWN** 



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153



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